

Title (en)
GLASS INSPECTION SYSTEMS AND METHODS FOR USING SAME

Title (de)
GLASPRÜFUNGSSYSTEM UND VERFAHREN ZU SEINER VERWENDUNG

Title (fr)
SYSTEMES D'INSPECTION DE VERRE ET PROCEDES D'UTILISATION

Publication
EP 1866625 A4 20101229 (EN)

Application
EP 06749504 A 20060406

Priority

- US 2006013012 W 20060406
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Abstract (en)
[origin: WO2006108137A2] Several different inspection systems and methods are described herein that identify defects (e.g., inclusions, onclusions, scratches, stains, blisters, cords or other imperfections associated with surface discontinuities or material non-homogeneities) on or within a glass sheet.

IPC 8 full level
G01N 21/00 (2006.01); **G01N 21/89** (2006.01); **G01N 21/90** (2006.01)

CPC (source: EP KR)
G01N 21/21 (2013.01 - KR); **G01N 21/45** (2013.01 - KR); **G01N 21/896** (2013.01 - EP KR); **G01N 21/958** (2013.01 - KR); **G01N 21/21** (2013.01 - EP); **G01N 21/45** (2013.01 - EP); **G01N 21/958** (2013.01 - EP); **G01N 2021/1774** (2013.01 - EP KR); **G01N 2021/8965** (2013.01 - EP KR); **G01N 2201/0612** (2013.01 - EP KR); **G01N 2201/0635** (2013.01 - EP KR); **G01N 2201/0638** (2013.01 - EP KR)

Citation (search report)

- [X] JP H04178545 A 19920625 - FUJI PHOTO FILM CO LTD
- [A] WO 2004017099 A2 20040226 - GREEN VISION SYSTEMS LTD [IL], et al
- [A] US 4340304 A 19820720 - MASSIE NORBERT A
- [A] SU 1260773 A1 19860930 - SP KT B I RADIOFIZIKI ELEKTRON [SU]
- [A] JP S57120804 A 19820728 - HITACHI METALS LTD
- [A] JP 2001041719 A 20010216 - CANON KK
- [A] US 2003210402 A1 20031113 - LIBINSON ALEXANDER [IL], et al
- [A] US 6040900 A 20000321 - CHEN XIAOLU [US]
- [A] JP H0579994 A 19930330 - KOWA CO
- See references of WO 2006108137A2

Cited by
DE102013105693A1; WO2014195296A1

Designated contracting state (EPC)
DE FR

DOCDB simple family (publication)
WO 2006108137 A2 20061012; WO 2006108137 A3 20061116; CN 101175986 A 20080507; CN 101175986 B 20101013; EP 1866625 A2 20071219; EP 1866625 A4 20101229; JP 2008536127 A 20080904; KR 20070121820 A 20071227; TW 200706859 A 20070216; TW I360652 B 20120321

DOCDB simple family (application)
US 2006013012 W 20060406; CN 200680016105 A 20060406; EP 06749504 A 20060406; JP 2008505569 A 20060406; KR 20077025683 A 20071105; TW 95112334 A 20060406